

# Development of externally triggerable optical pump-probe scanning tunneling microscope with time resolution of approximately 70 ps

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The combination of optical pump-probe (OPP) methods with scanning tunneling microscopy (STM) enables us to investigate carrier dynamics with nanoscale spatial resolution for exploring novel functionalities in advanced materials. Such OPP-STM systems, employing the delay-time modulation technique to eliminate thermal expansion of the tip due to the change in light intensity, have been developed and applied for studying atomic-scale carrier dynamics on semiconductor surfaces [1, 2]. However, operating the OPP-STM systems required considerable skills and experience. To overcome this difficulty, a compact tabletop OPP system, in which the timing of laser pulses is electrically controlled by external triggers using the field-programmable gate array (FPGA), has been recently reported [3].

In this study, we newly designed and constructed an externally triggerable OPP-STM, aiming not only to realize highly stable measurements but also for easy system implementation and maintenance. Time resolution determined by the laser pulse width, jitter and the trigger pulse jitter was estimated to be about 70 ps. The OPP-STM measurements were conducted on GaAs(110) surface, revealing local carrier dynamics depending on surface structures such as the step edge and nanoscale defects. The experimental result clearly represents potential capabilities of this technique for a wide range of materials.

This work was supported by A-STEP NexTEP-B type program (Grant No. AS0116003) from Japan Science and Technology Agency (JST).

## References:

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